



Sheet 1 of 1

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PATENT AND TRADEMARK OFFICE		APPLICANT Christopher L. Wooten, et al.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		FILING DATE October 11, 2001	GROUP 2623

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
WT	5,982,920	11/09/99	Tobin, Jr., et al.	—	—	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION

OTHER DOCUMENTS (Including Author, Title, Date Pertinent Pages, Etc.)

WT	Using SSA to Measure the Efficacy of Automated Defect Data Gathering, Kenneth W. Tobin, Shaun S. Gleason, Thomas P. Karnowski, David Guidry, Micro Magazine, April 98, Analysis & Metrology, p.27.
WT	Spatial Signature Analysis: Rapidly Tracing Semiconductor Defects to Manufacturing Problems, Kenneth W. Tobin, Shaun S. Gleason and Thomas P. Karnowski.
WT	An Integrated Spatial Signature Analysis and Automatic Defect Classification System, Shaun S. Gleason, Kenneth W. Tobin, Thomas P. Karnowski.

EXAMINER WT DATE CONSIDERED 8-10-05

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.